

Search Notes

Application/Control No.

10/764,481

Examiner

MARK A. MAIS

Applicant(s)/Patent under
Reexamination

HIYAMA ET AL.

Art Unit

2419

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|-------------------|------------|----------|
| 370 | 310 328 | 11/20/2008 | MAM |
| | 329 331 | | |
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INTERFERENCE SEARCHED

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| Search | Performed | 11/20/2008 | MAM |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---|------------|------|
| See Inventorship Search | 6/16/2007 | MAM |
| See Attached Electronic Search | 6/16/2007 | MAM |
| See Attached Electronic Search [updated] | 3/30/2008 | MAM |
| See Attached Electronic Search [updated] | 8/18/2008 | MAM |
| See Attached Electronic Search [updated] | 11/20/2008 | MAM |
| See Interference Search | 11/20/2008 | MAM |
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